

Abstract

Method and Apparatus for Training Defect Detection Model, and Electronic Device

Disclosed are a method and apparatus for training a defect detection model, and an electronic device. The method includes: acquiring a training sample set and first defect label information corresponding to each group of samples in the training sample set, wherein each group of samples in the training sample set includes a defect image and a template image corresponding to the defect image, and the first defect label information includes first category information and first position information of each defect in the defect image; determining a target loss function; and by means of using Stochastic Gradient Descent (SGD), training a model to be trained with the training sample set, the defect label information, and the target loss function to obtain a target defect detection model, wherein the target defect detection model is configured to determine defect position information and defect category information in a defect image to be detected.

Figure 2